

## 1. Description

The FDD6680AS is designed to replace a single MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low  $R_{DS(ON)}$  and low gate charge. The performance of the FDD6680AS as the low-side switch in a synchronous rectifier is indistinguishable from the performance of the FDD6680A in parallel with a Schottky diode.

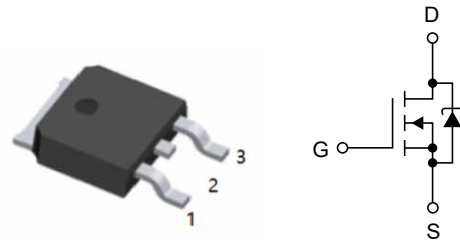
## 2. Features

- $V_{DS(V)} = 30V$
- $I_D = 50A$  ( $V_{GS} = 10V$ )
- $R_{DS(ON)} < 10.5m\Omega$  ( $V_{GS} = 5V$ )
- $R_{DS(ON)} < 13m\Omega$  ( $V_{GS} = 4.5V$ )
- Includes SyncFET Schottky body diode
- Low gate charge (21nC typical)
- High performance trench technology for extremely low  $R_{DS(ON)}$
- High power and current handling capability

## 3. Pinning information

Pin	Symbol	Description
1	G	GATE
2	D	DRAIN
3	S	SOURCE

TO-252(DPAK)  
top view



## 4. Absolute Maximum Ratings $T_A = 25^\circ C$

Parameter	Symbol	Rating	Units
Drain-Source Voltage	$V_{DSS}$	30	V
Gate-Source Voltage	$V_{GSS}$	$\pm 20$	V
Drain Current - Continuous (Note 3)	$I_D$	55	A
-Pulsed (Note 1a)		100	A
Power Dissipation for Single Operation (Note 1)	$P_D$	60	W
		3.1	W
		1.3	W
Operating and Storage Junction Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ C$



## 5. Thermal Characteristics

Parameter	Symbol	Rating	Units
Thermal Resistance, Junction-to-Case (Note 1)	$R_{\theta JC}$	2.1	°C/W
Thermal Resistance, Junction-to-Ambient (Note 1a)	$R_{\theta JA}$	40	°C/W
Thermal Resistance, Junction-to-Ambient (Note 1b)	$R_{\theta JA}$	96	°C/W



## 6. Electrical Characteristic (T<sub>A</sub>=25°C unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Drain-Source Avalanche Energy	W <sub>DSS</sub>	Single Pulse, V <sub>DD</sub> =15V, I <sub>D</sub> =13.5A		54	205	mJ
Drain-Source Avalanche Current	I <sub>AR</sub>				13.5	A
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =1mA	30			V
Breakdown Voltage Temperature Coefficient	$\frac{\Delta BV_{DSS}}{\Delta T_J}$	I <sub>D</sub> =1mA Referenced to 25°C		29		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V			500	μA
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =1mA	1	1.4	3	V
Gate Threshold Voltage Temperature Coefficient	$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	I <sub>D</sub> =1mA Referenced to 25°C		-3		mV/°C
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =12.5A		8.6	10.5	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A		10.3	13	mΩ
On-State Drain Current	I <sub>D(ON)</sub>	V <sub>GS</sub> =10V, V <sub>DS</sub> =5V	50			A
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =15V, I <sub>D</sub> =12.5A		44		S
Input Capacitance	C <sub>iss</sub>			1200		pF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz		350		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			120		pF
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> =15mV, f=1MHz		1.6		Ω
Turn-On Delay Time	t <sub>D(on)</sub>			10	20	ns
Turn-On Rise Time	t <sub>r</sub>	V <sub>DD</sub> =15V, I <sub>D</sub> =1A		6	12	ns
Turn-Off Delay Time	t <sub>D(off)</sub>	V <sub>GS</sub> =10V, R <sub>GEN</sub> =6Ω		28	45	ns
Turn-Off Fall Time	t <sub>f</sub>			12	22	ns
Turn-On Delay Time	t <sub>D(on)</sub>			14	25	ns
Turn-On Rise Time	t <sub>r</sub>	V <sub>DD</sub> =15V, I <sub>D</sub> =1A		13	23	ns
Turn-Off Delay Time	t <sub>D(off)</sub>	V <sub>GS</sub> =4.5V, R <sub>GEN</sub> =6Ω		20	32	ns
Turn-Off Fall Time	t <sub>f</sub>			11	20	ns

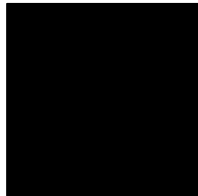


Total Gate Charge, $V_{GS}=10V$	$Q_{g(TOT)}$	$V_{DS}=15V, I_D=12.5A$		21	29	nC
Total Gate Charge, $V_{GS}=5V$	$Q_g$			11	15	nC
Gate–Source Charge	$Q_{gs}$			3		nC
Gate–Drain Charge	$Q_{gd}$			4		nC
Maximum Continuous Drain–Source Diode Forward Current	$I_S$				4.4	A
Drain–Source Diode Forward Voltage	$V_{SD}$	$V_{GS}=0V, I_S=4.4A$ (Note 2)		0.5	0.7	V
		$V_{GS}=0V, I_S=7A$ (Note 2)		0.6	0.7	V
Diode Reverse Recovery Time	$t_{rr}$	$I_F=12.5A$		17		ns
Diode Reverse Recovery Charge	$Q_{rr}$	$dI/dt=300A/\mu s$ (Note 3)		11		nC

Notes:

1.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.

$R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



■ a)  $R_{\theta JA}=40^{\circ}C/W$  when mounted on a  $1in^2$  pad of 2oz copper.



■ b)  $R_{\theta JA}=96^{\circ}C/W$  when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

3. Maximum current is calculated as:  $\sqrt{\frac{P_D}{R_{DS(ON)}}}$

where  $P_D$  is maximum power dissipation at  $T_C=25^{\circ}C$  and  $R_{DS(ON)}$  is at  $T_{J(max)}$  and  $V_{GS}=10V$ . Package current limitation is 21A.

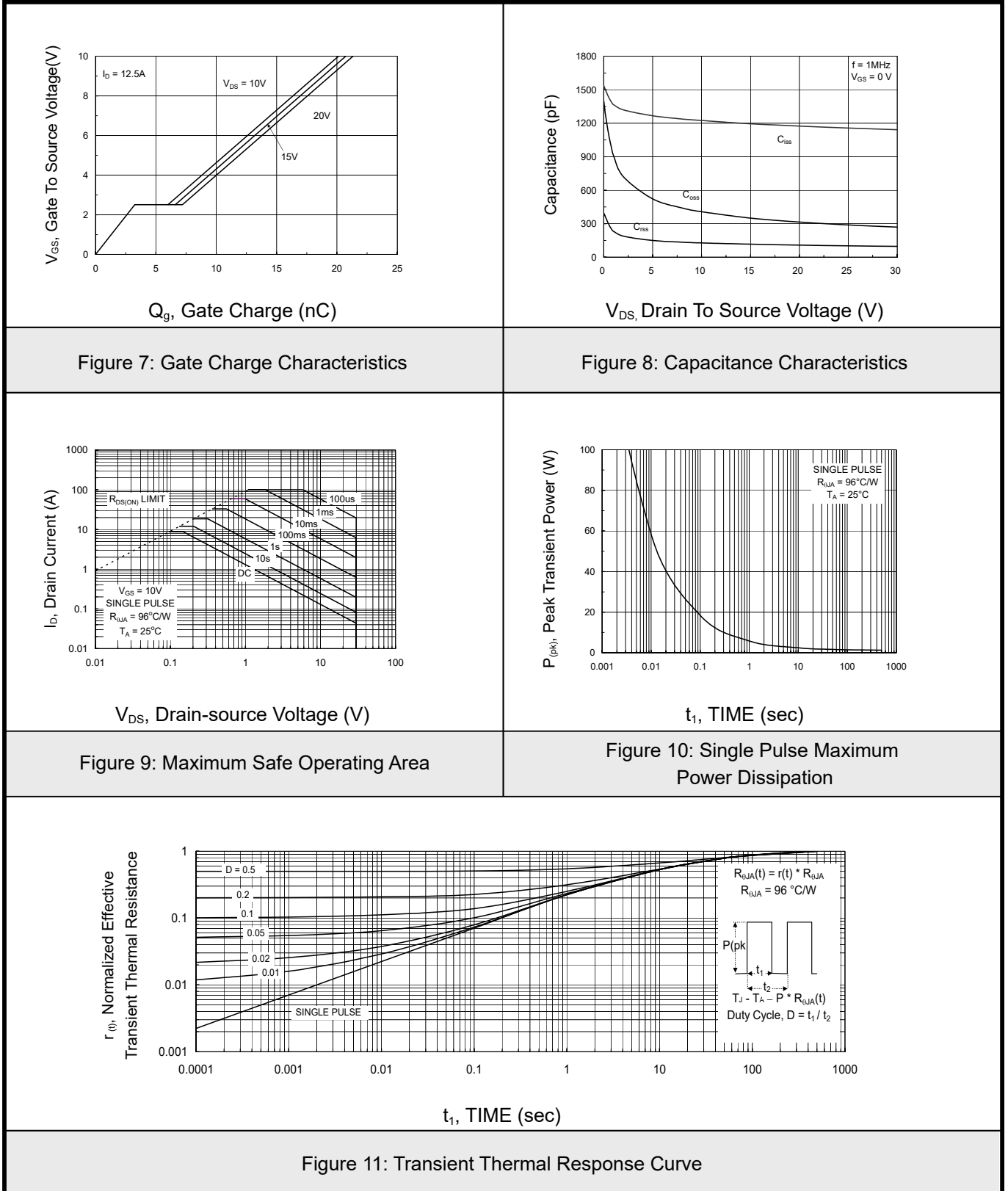


## 7.1 Typical characteristic

<p>Figure 1: On-Region Characteristics</p>	<p>Figure 2: On-Resistance Variation with Drain Current and Gate Voltage</p>
<p>Figure 3: On-Resistance Variation with Temperature</p>	<p>Figure 4: On-Resistance Variation with Gate-to-Source Voltage</p>
<p>Figure 5: Transfer Characteristics</p>	<p>Figure 6: Body Diode Forward Voltage Variation with Source Current and Temperature</p>



## 7.2 Typical characteristic





## 7.3 Typical characteristic

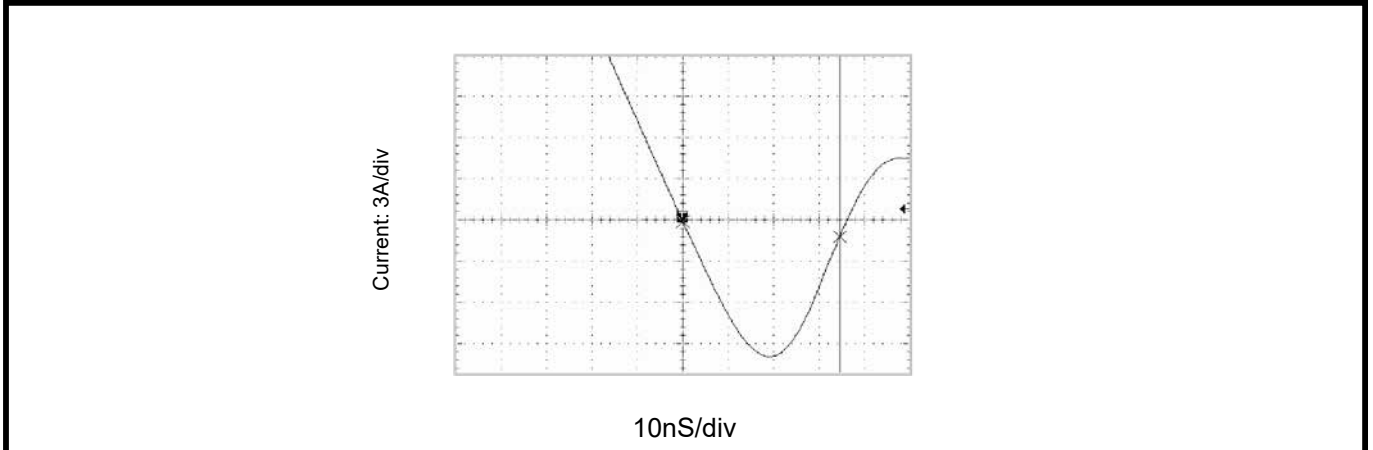


Figure 12: FDD6680AS SyncFET body diode reverse recovery characteris

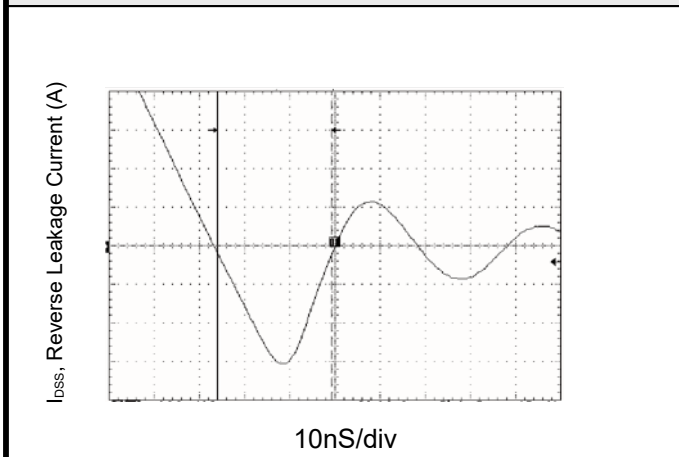


Figure 13: Non-SyncFET (FDD6680) body diode reverse recovery characteristic

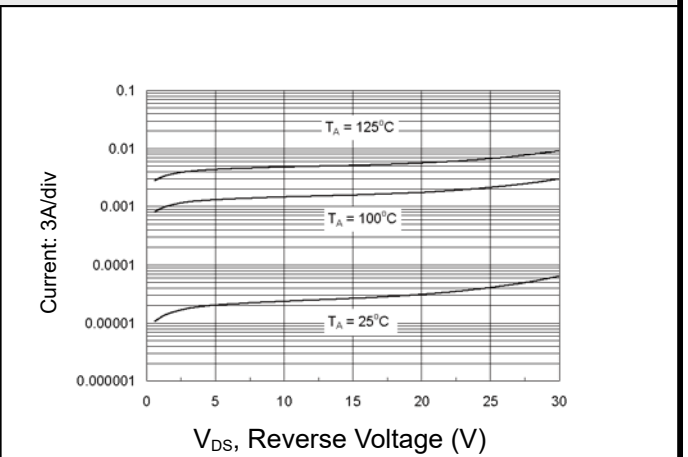


Figure 14: SyncFET body diode reverse leakage versus drain-source voltage and temperature

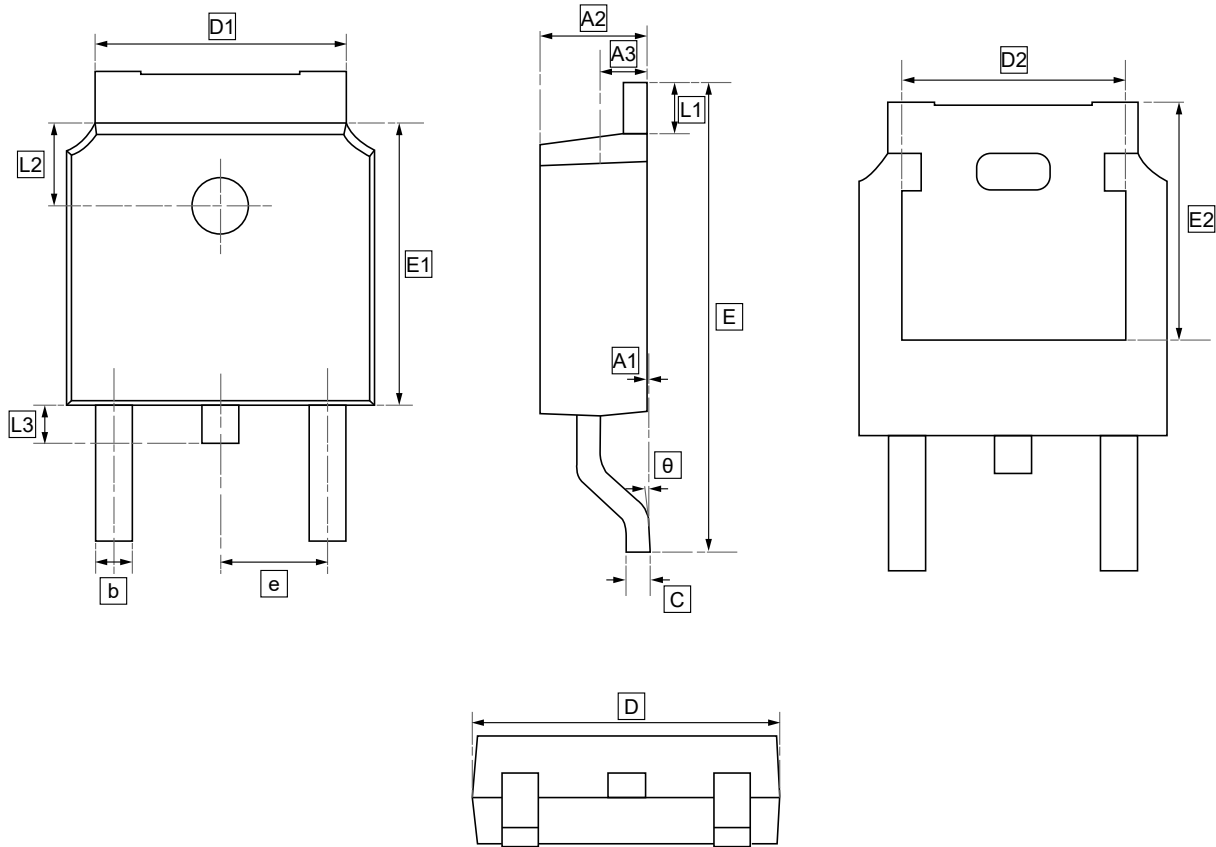
This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDD6680AS.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDD6680).



## 8.TO-252 Package Outline Dimensions

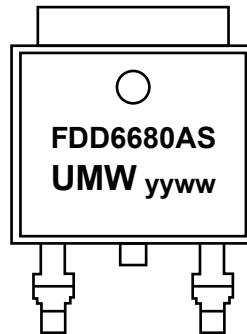


### DIMENSIONS (mm are the original dimensions)

Symbol	A1	A2	A3	b	c	D	D1	D2	E	E1	E2	e	L1	L2	L3	θ
<b>Min</b>	0.00	2.18	0.90	0.65	0.46	6.35	4.95	4.32	9.40	5.97	5.21	2.286	0.89	1.70	0.60	0.00
<b>Max</b>	0.13	2.39	1.10	0.85	0.61	6.73	5.46	4.90	10.41	6.22	5.38	BSC	1.27	1.90	1.00	8.00



## 9. Ordering information



yy: Year Code  
ww: Week Code

Order Code	Package	Base QTY	Delivery Mode
UMW FDD6680AS	TO-252	2500	Tape and reel



## **10.Disclaimer**

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